

Notice of References Cited	Application/Control No. 10/595,332		Applicant(s)/Patent Under Reexamination DENNERT ET AL.	
	Examiner QUN SHEN		Art Unit 4153	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,454,032 A	09-1995	Pinard et al.	379/167.05
*	B	US-5,711,006 A	01-1998	Brochu et al.	455/445
*	C	US-6,141,556 A	10-2000	Dougherty et al.	455/445
*	D	US-6,587,683 B1	07-2003	Chow et al.	455/417
*	E	US-6,738,615 B1	05-2004	Chow et al.	455/415
*	F	US-2004/0174975 A1	09-2004	Sylvain et al.	379/211.01
*	G	US-2004/0229601 A1	11-2004	Zabawskij et al.	455/417
*	H	US-2005/0026600 A1	02-2005	Hymel, James A.	455/417
*	I	US-7,437,148 B1	10-2008	Vaghi et al.	455/417
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 740482 A1	10-1996	European Patent	PROUDLER, GRAEME JOHN	
*	O	WO 01/01708 A1	01-2001	PCT	Immonen, Pekka	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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